

**Search Notes**

Application/Control No.

10/814,505

Examiner

Christopher B. Shin

Applicant(s)/Patent under  
Reexamination

KEYS ET AL.

Art Unit

2181

**SEARCHED**

Class	Subclass	Date	Examiner
710	105, 305- 315, 52- 56, 72	8/2/2006	CBS
709	208, 230	8/2/2006	CBS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
710	313, 315	8/2/2006	CBS
710	56, 72	8/2/2006	CBS
709	230	8/2/2006	CBS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PALM (INVENTOR FOR DOUBLE PATENTING)	8/1/2006	CBS
EAST (EPO, USPAT, US-PGPUB, JPO, DERWENT IBMTDB,USOCR)	8/2/2006	CBS